

November 2009
UniFET-IITM

FDD5N50NZF N-Channel MOSFET 500V, 3.7A, 1.75 Ω

Features

- $R_{DS(on)} = 1.47\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 1.85A$
- Low Gate Charge (Typ. 9nC)
- Low C_{rss} (Typ. 4pF)
- · Fast Switching
- 100% Avalanche Tested
- Improved dv/dt Capability
- · ESD Imoroved Capability
- RoHS Compliant

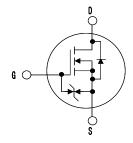


Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advance technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switching mode power supplies and active power factor correction.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDD5N50NZF	Units	
V _{DSS}	Drain to Source Voltage			500	V	
V _{GSS}	Gate to Source Voltage			±25	V	
1	Drain Current	-Continuous (T _C = 25°C)		3.7	۸	
ID	Diam Current	-Continuous ($T_C = 100^{\circ}C$)	-Continuous (T _C = 100°C)		Α	
I _{DM}	Drain Current	- Pulsed	(Note 1)	14	Α	
E _{AS}	Single Pulsed Avalanche Er	nergy	(Note 2)	165	mJ	
I _{AR}	Avalanche Current		(Note 1)	3.3	Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	6.25	mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	15	V/ns	
D	Dower Discipation	$(T_C = 25^{\circ}C)$		62.5	W	
P_{D}	Power Dissipation	- Derate above 25°C		0.5	W/°C	
T _J , T _{STG}	Operating and Storage Tem	perature Range		-55 to +150	°C	
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C	

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDD5N50NZF	Units		
$R_{\theta JC}$	Thermal Resistance, Junction to Case	2	°C/W		
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient 62.5				

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD5N50NZF	FDD5N50NZFTM	D-PAK	380mm	16mm	2500

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter Test Conditions		Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$, $V_{GS} = 0 V$, $T_C = 25 ^{\circ} C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$, Referenced to 25°C	-	0.5	-	V/°C
1	Zoro Coto Voltago Proin Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	10	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 400V, V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μА

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 1.85A$	1	1.47	1.75	Ω
g _{FS}	Forward Transconductance	$V_{DS} = 20V, I_D = 1.85A$ (Note 4)	ı	4.2	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05V V 0V		-	365	485	pF
C _{oss}	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		-	50	65	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1101112		-	4	8	pF
$Q_{g(tot)}$	Total Gate Charge at 10V			-	9	12	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400 V I_{D} = 3.7 A$		-	2	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V	(Note 4, 5)	-	4	-	nC

Switching Characteristics

	_						
t _{d(on)}	Turn-On Delay Time			-	12	35	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_{D} = 3.7A$		-	19	50	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10V, R_{GEN} = 25\Omega$		-	31	70	ns
t _f	Turn-Off Fall Time	(Not	e 4. 5)	-	22	55	ns

Drain-Source Diode Characteristics

IS	Maximum Continuous Drain to Source Diode Forward Current			-		3.7	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current			=	-	14	Α
V_{SD}	Drain to Source Diode Forward Voltage V _{GS} = 0V, I _{SD} = 3.7A		-	-	1.5	V	
t _{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 3.7A$		-	87	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	0.15	-	μС

- Notes:

 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 23mH, I $_{AS}$ = 3.7A, V $_{DD}$ = 50V, R $_{G}$ = 25 Ω , Starting T $_{J}$ = 25 $^{\circ}C$
- 3. $I_{SD} \le 3.7 \text{A}$, di/dt $\le 200 \text{A}/\mu\text{s}$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$
- 4. Pulse Test: Pulse width $\leq 300 \mu s, \, \text{Dual Cycle} \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

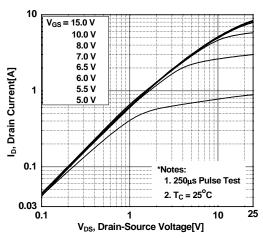


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

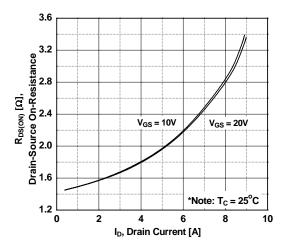


Figure 5. Capacitance Characteristics

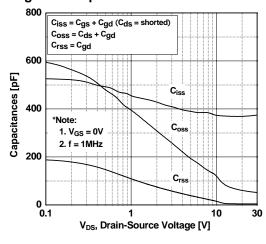


Figure 2. Transfer Characteristics

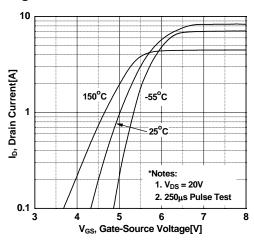


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

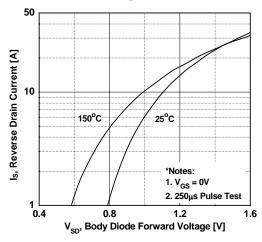
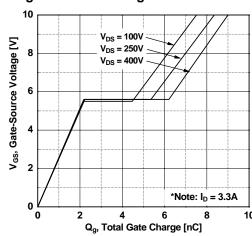


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

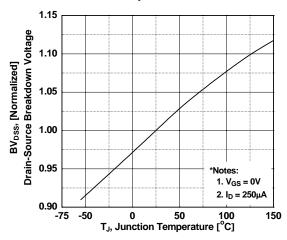


Figure 9. Maximum Safe Operating Area vs. Case Temperature

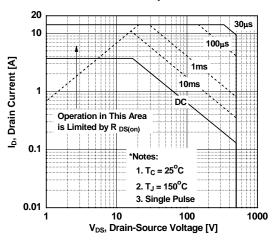


Figure 10. Maximum Drain Current

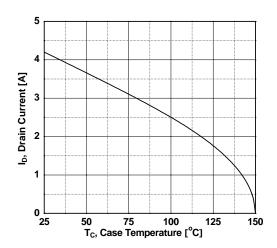
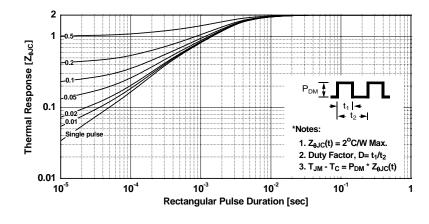
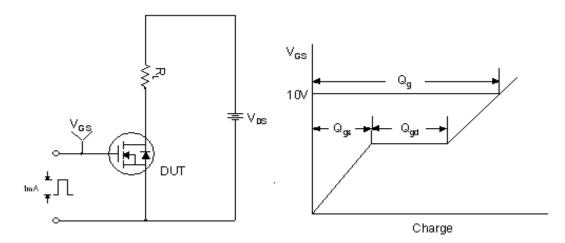


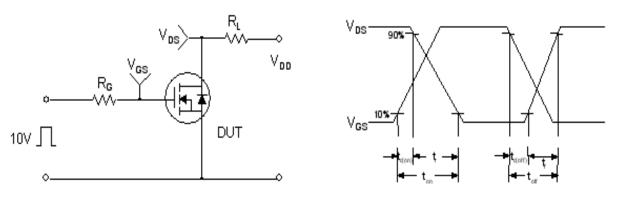
Figure 11. Transient Thermal Response Curve



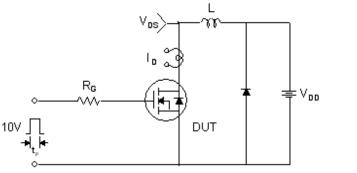
Gate Charge Test Circuit & Waveform

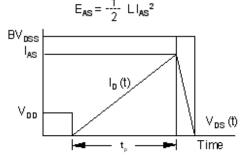


Resistive Switching Test Circuit & Waveforms

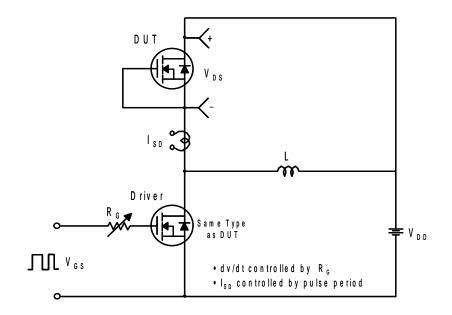


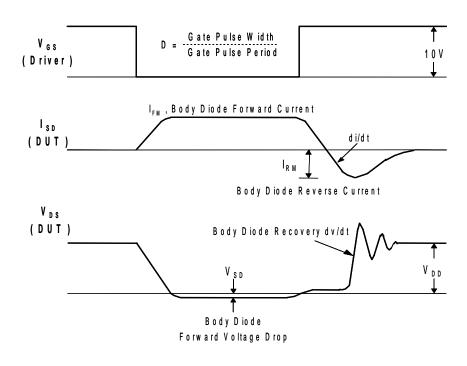
Unclamped Inductive Switching Test Circuit & Waveforms





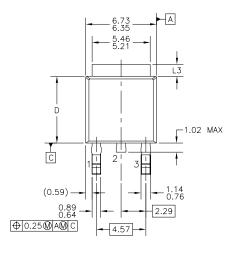
Peak Diode Recovery dv/dt Test Circuit & Waveforms

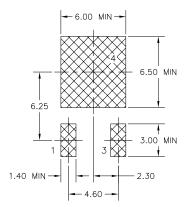




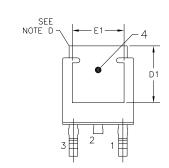
Mechanical Dimensions

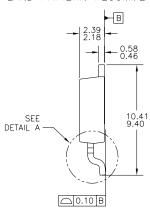
D-PAK

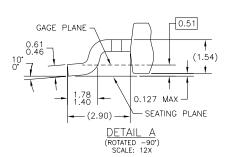




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 B) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA & AB, DATED NOV. 1999.

 C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

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 E) DIMENSIONS L3.D.E1&D1 TABLE:

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	D	5.97-6.22	5.33-5.59					
	E1	4.32 MIN	3.81 MIN					
	D1	5.21 MIN	4.57 MIN					

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